IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

TAKENAKA Atty. Ref.: 4074-9

Serial No. Unknown Group:

Filed: October 29, 2003 Examiner:

For: METHOD OF SEMICONDUCTOR DEVICE FABRICATION

October 29, 2003

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT

As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the references listed on the attached form PTO-1449, a copy of each of which is enclosed. This is not to be construed as a representation that a search has been made or that no better prior art exists, or that a reference is relevant merely because cited.

The Examiner is requested to initial the attached form PTO-1449 and to return a copy of the initialed document to the undersigned as an indication that the attached references have been considered and made of record.

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION		ATTY, DOCKET NO. SERIAL NO.					
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		APPLICANT	- -				
		TAKENAKA					
(Use several sheets if necessary)		FILING DATE GROUP					
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		U.S. PATEN	T DOCUMENTS				
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Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.